



<p>Searched</p> 	<p>Application/Control No.</p> <p>10052847</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>YEUNG ET AL.</p>
	<p>Examiner</p> <p>Nawaz, Asad M</p>	<p>Art Unit</p> <p>2155</p>

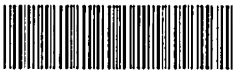
Class	SubClass	Date	Examiner
709	202-207, 217-219, 223-238	10/1/06	AMN

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Interference Searched 	Application/Control No. 10052847	Applicant(s)/Patent Under Reexamination YEUNG ET AL.
	Examiner Nawaz, Asad M	Art Unit 2155

Class	SubClass	Date	Examiner
709	225, 217,226,232	10/1/06	AMN

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Search Notes 	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10052847	YEUNG ET AL.
	Examiner Nawaz, Asad M	Art Unit 2155

Notes	Date	Examiner
East Search (USPAT; USPGPUB; EPO; JPO; DERWENT; IBM_TDB)	10/1/06	AMN
Updated PgPub Search	10/1/06	AMN
Inventor Name Search for ODP	9/27/06	AMN
NPL Search (IEEE Xplore, ACM Digital Library)	9/27/06	AMN
Consulted Supervisory Examiner Saleh Najjar regarding allowability	9/26/06	AMN
Consulted Primary Examiner Phillip Tran regarding allowability	9/25/06	AMN
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